TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSVI)

2SK3561

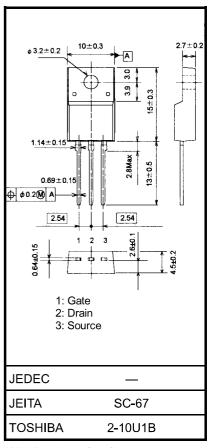
Switching Regulator Applications

Unit: mm

- Low drain-source ON resistance: RDS (ON) = 0.75Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 6.5S$ (typ.)
- Low leakage current: $IDSS = 100 \mu A (VDS = 500 V)$
- Enhancement mode: $V_{th} = 2.0 \sim 4.0 \text{ V} \text{ (V}_{DS} = 10 \text{ V}, I_D = 1 \text{ mA)}$

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	500	V	
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	500	V	
Gate-source voltage		V_{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	8	А	
	Pulse (t = 1 ms) (Note 1)	I _{DP}	32		
Drain power dissipat	ion (Tc = 25°C)	P_{D}	40	W	
Single pulse avalanche energy (Note 2)		E _{AS}	312	mJ	
Avalanche current		I _{AR}	8	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	4	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	- 55~150	°C	



Weight: 1.7 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.125	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

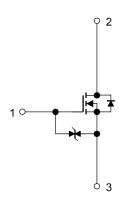
Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}(\text{initial})$, L = 8.3 mH, $I_{AR} = 8 \text{ A}$, $R_G = 25 \Omega$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

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This transistor is an electrostatic-sensitive device. Please handle with caution.



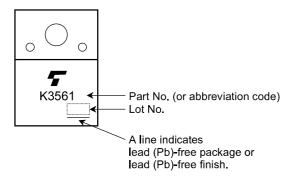
Electrical Characteristics (Ta = 25°C)

Chara	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage curr	rent	I _{GSS}	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Gate-source brea	kdown vo l tage	V _(BR) GSS	$I_G=\pm 10~\mu A,~V_{DS}=0~V$	±30	_	_	V
Drain cut-off curre	ent	I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V		_	100	μΑ
Drain-source brea	akdown voltage	V (BR) DSS	$I_D = 10$ mA, $V_{GS} = 0$ V	500	_	_	V
Gate threshold vo	Itage	V_{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 4 A	_	0.75	0.85	Ω
Forward transfer a	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 4 A	3.0	6.5	_	S
Input capacitance		C _{iss}		_	1050	_	
Reverse transfer capacitance		C _{rss}	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	10	_	pF
Output capacitance		C _{oss}			110	_	
Switching time	Rise time	t _r	$\begin{array}{c c} 10 \text{ V} \\ \text{VGS} \\ 0 \text{ V} \end{array}$ $\begin{array}{c c} \text{I}_D = 4 \text{ A} & \text{V}_{\text{OUT}} \\ \text{OUT} \\ \text$	_	26	_	
	Turn-on time	t _{on}			45		ne
	Fall time	t _f			38		ns
	Turn-off time	t _{off}	Duty \leq 1%, $t_W = 10 \mu s$		130	_	
Total gate charge		Qg		_	28	_	
Gate-source charge		Q _{gs}	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 8 \text{ A}$		16	_	nC
Gate-drain charge		Q _{gd}		_	12	_	

Source-Drain Ratings and Characteristics (Ta = 25°C)

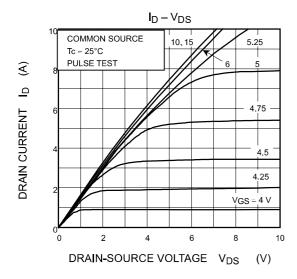
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_			8	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	32	Α
Forward voltage (diode)	V _{DSF}	$I_{DR} = 8 \text{ A}, V_{GS} = 0 \text{ V}$		_	-1.7	V
Reverse recovery time	t _{rr}	$I_{DR} = 8 \text{ A}, V_{GS} = 0 \text{ V},$		1200		ns
Reverse recovery charge	Q _{rr}	dI _{DR} /dt = 100 A/μs		10	_	μС

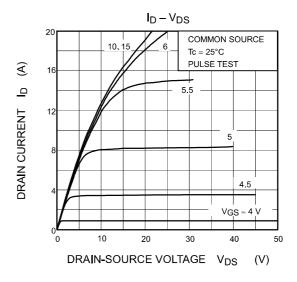
Marking

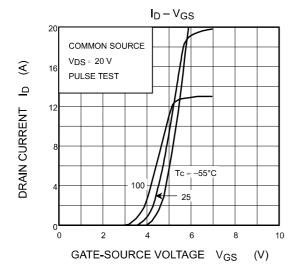


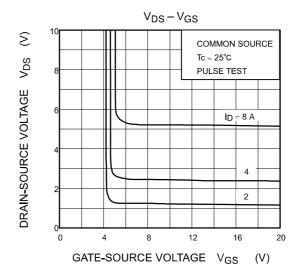
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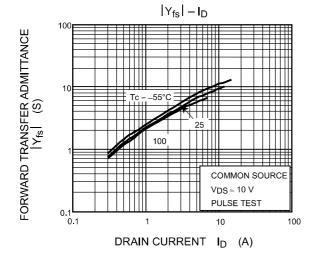
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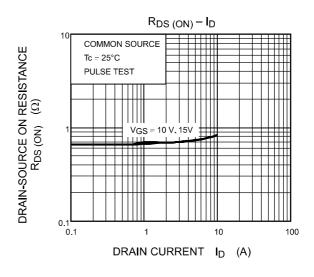


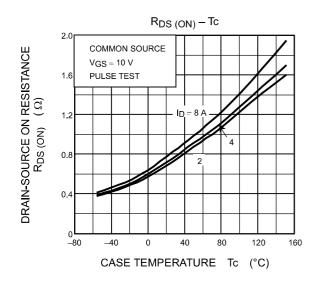


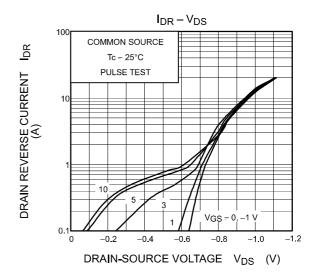


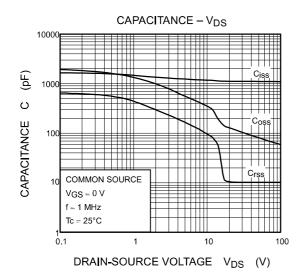


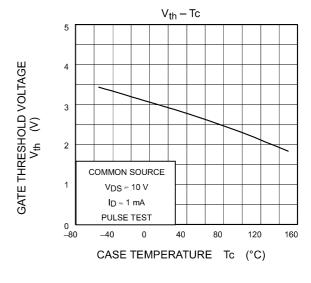


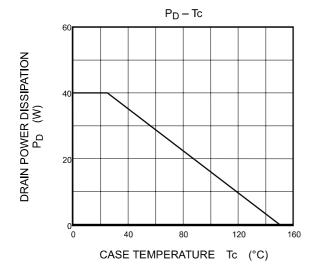


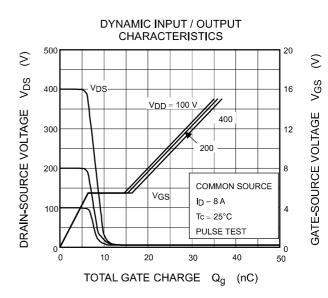


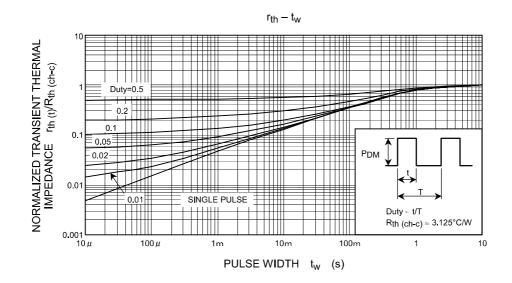


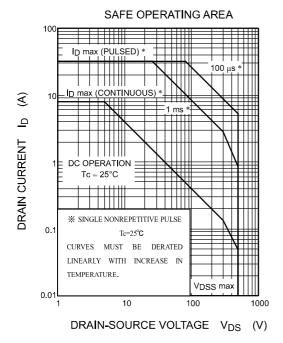


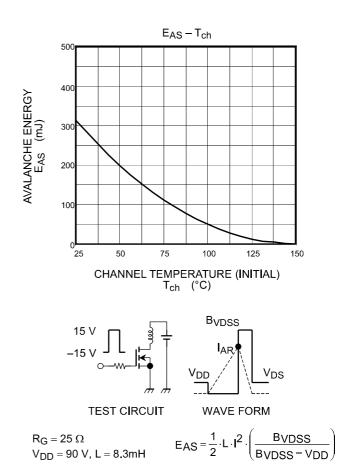












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TOSHIBA

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